PTO/SB/08a (05-07)
Approved for use through 11/30/2007 OMB 0851-0231
U.S. Patent and Trademark Office, U.S. DEPARTMENT OF COMMERCE to a collection of information unless it contains a valid OMB control number. Under the Paperwork Reduction Act of 1995, no persons are required

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(Not for submission under 37 CFR 1.99)

Application Number		10599404			
Filing Date		2006-09-28			
First Named Inventor	Stein	Stein KUIPER, ET AL			
Art Unit		2875			
Examiner Name					
Attamen Dealest Number		NI 04022E			

lte o Patent Number 6002661 4890903	Kind Code ¹	1999-12-14	Name of Patentee or Applicant of cited Document ABE ET AL	Pages,Columns,Lines where Relevant Passages or Relevar Figures Appear			
4890903			ABE ET AL				
		1990-01-02					
4583824			TREISMAN ET AL				
TOUGHT.		1986-04-22	LEA				
5880896		1999-03-09	ISHII ET AL				
o add additional U.S. Pate	nt citatio	n information pl	lease click the Add button.	Add			
U.S.PATENT APPLICATION PUBLICATIONS Remove							
aminer Cite Publication Number Kind Publication Name of Patentee of Applicant R		Pages,Columns,Lines where Relevant Passages or Relevan Figures Appear					
20020135908	A1	2002-09-26	RYUTOV ET AL				
20030006140	A1	2003-01-09	VACCA ET AL				
o add additional U.S. Pub	lished Ap	plication citation	n information please click the Ad-	d button, Add			
-	20020135908 20030006140	Publication Number Code1	Publication Number Code ¹ Date 2002013/908 A1 2002-09-26 20030006140 A1 2003-01-09 acd additional U.S. Published Application citation	Publication Number Code ¹ Date of cited Document			

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Not for submission under 37 CFR 1.99)

Application Number		10599404		
Filing Date		2006-09-28		
First Named Inventor	Stein KUIPER, ET AL			
Art Unit		2875		
Examiner Name				
A		NII 04022E		

Pages,Columns,Lines

Examiner Initial*	Cite No	Foreign Document Number ³	Country Code ² j	Kind Code ⁴	Publication Date	Applicant of cited Document	where Relevant Passages or Relevant Figures Appear	Τs
	1	03069380	wo	A1	2003-08-21	KPENV		
	2	2000356751	JP	A	2000-12-26	CANON INC		
If you wis	h to a	ı dd additional Foreign P	atent Document	citation	information pl	lease click the Add buttor	Add	Н
			NON-PATE	NT LITE	RATURE DO	CUMENTS	Remove	
Examiner Initials*	Cite No		nal, serial, symp	osium,	catalog, etc), o	the article (when appropriate, pages(s), volume-is		Ţ5
	1	HELENE YOCKELL-LEUEVRE, ET AL: Optical Tests of Nancengineered Liquid Mirrors, APPLIED OPTICS Vol. 42, No. 10, April 2003, pages 1882-1896						
	P. R. LAIRD, ET AL: Ferraflud Based Defamable Mirrors - A New Approach to Adaptive Optics Using Liquid Mirrors, PROCEEDINGS SPIE, Vol. 4839, pages 733-739							
	3	ERMANNO F. BORRA, QC, 516: May 10,1999,			HE ASTROPHY	SICAL JOURNAL, UNIVER	SITY LAVAL, QUEBEC,	
	4	JAMES R LEGER ET A OPTICS LETTERS, VO				OR MODE SHAPING OF A	ND: YAG LASER",	
	5	C. PARE ET AL; "CUST QUANTUM ELECTRON				DED-PHASE MIRRORS*, IS 362.	EEE JOURNAL OF	
	6	H. KOGELNIK ET AL; "I 1966.	ASER BEAMS A	ND RES	ONATORS*, AP	PLOPT., VOL. 5, NO. 10, I	PP 1550-1567, OCT.	

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Not for submission under 37 CFR 1.99)	Application Number		10599404	
	Filing Date		2006-09-28	
	First Named Inventor Stein		n KUIPER, ET AL	
	Art Unit		2875	
	Examiner Name			
	Attorney Docket Number		NL040335	

 ,—		_
7	A E. SIEGMAN ET AL; "LASERS", UNIV. SCIENCE BOOKS, MILL VALLEY, CA, US, CHAPTER 19.	

Date Considered

If you wish to add additional non-patent literature document citation information please click the Add button Add

EXAMINER SIGNATURE

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through a citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

See Kind Code of USPTO Patent Documents at time USETO.GGU or MREP 991.94. * Enter office that issued the document, by the two-letter code (MPC)
Standard 57.3. * "For uppease patent counters, the orbidation of the year of the register time precede the serial review of the patent document.
Ident of document by the appropriate symbols as endicated on the document under WIPO Standard 57.1.6 if possible. **Applicant is to place a check mark here if English inaurages translation is altitude.

Examiner Signature